
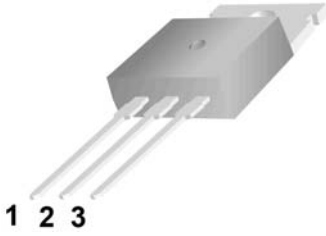
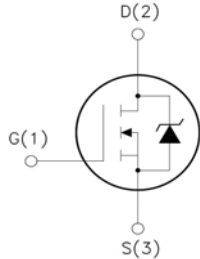


<p><b>4N90</b></p> <p><b>Features:</b></p> <ul style="list-style-type: none"> <li><input type="checkbox"/> Low Intrinsic Capacitances.</li> <li><input type="checkbox"/> Excellent Switching Characteristics.</li> <li><input type="checkbox"/> Extended Safe Operating Area.</li> <li><input type="checkbox"/> Unrivalled Gate Charge :<math>Q_g=17nC</math> (Typ.).</li> <li><input type="checkbox"/> <math>BVDSS=900V, I_D=4A</math></li> <li><input type="checkbox"/> <math>R_{DS(on)} : 3.4 \Omega</math> (Max) @<math>V_G=10V</math></li> <li><input type="checkbox"/> 100% Avalanche Tested</li> </ul>	<p style="text-align: center;"><b>TO-220</b></p> <div style="text-align: right;">  </div> <div style="text-align: center;">  <p><b>1 2 3</b></p>  </div> <div style="text-align: right;"> <p>1.Gate (G)</p> <p>2.Drain (D)</p> <p>3.Source (S)</p> </div>
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### Absolute Maximum Ratings ( $T_a=25^\circ C$ unless otherwise noted)

Symbol	Parameter	Value	Unit
$V_{DSS}$	Drain-Source Voltage	900	V
$I_D$	Drain Current	$T_j=25^\circ C$	4.0
		$T_j=100^\circ C$	2.3
$V_{GS(TH)}$	Gate Threshold Voltage	$\pm 30$	V
$E_{AS}$	Single Pulse Avalanche Energy (note1)	570	mJ
$I_{AR}$	Avalanche Current (note2)	4	A
$P_D$	Power Dissipation ( $T_j=25^\circ C$ )	140	W
$T_j$	Junction Temperature(Max)	150	$^\circ C$
$T_{stg}$	Storage Temperature	-55~+150	$^\circ C$
$T_L$	Maximum lead temperature for soldering purpose, 1/8" from case for 5 seconds	300	$^\circ C$

### Thermal Characteristics

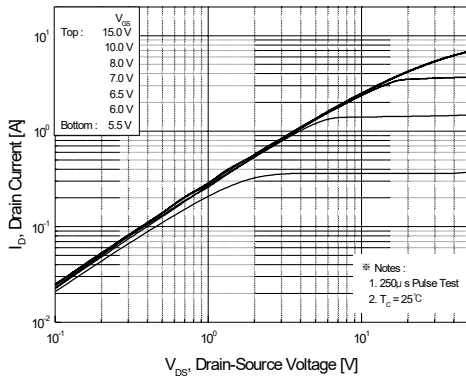
Symbol	Parameter	Typ.	Max.	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case	-	0.88	$^\circ C/W$
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	-	62.5	$^\circ C/W$

**Electrical Characteristics** (Ta=25°C unless otherwise noted)

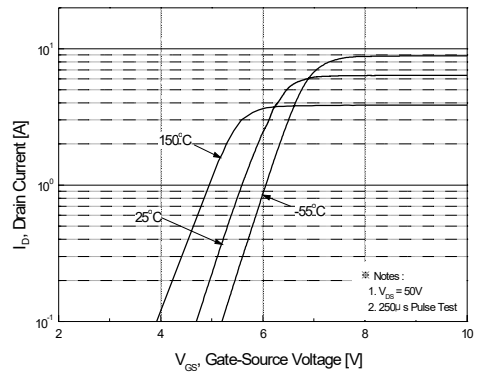
Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Unit
<b>Off Characteristics</b>						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	I <sub>D</sub> =250μA, V <sub>GS</sub> =0	900	-	-	V
ΔBV <sub>DSS</sub> /ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> =250μA, Reference to 25°C	-	1.05	-	V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =900V, V <sub>GS</sub> =0V	-	-	10	μA
		V <sub>DS</sub> =720V, T <sub>J</sub> =125°C	-	-	100	
I <sub>GSSF</sub>	Gate-body leakage Current, Forward	V <sub>GS</sub> =+30V, V <sub>DS</sub> =0V	-	-	100	nA
I <sub>GSSR</sub>	Gate-body leakage Current, Reverse	V <sub>GS</sub> =-30V, V <sub>DS</sub> =0V	-	-	-100	
<b>On Characteristics</b>						
V <sub>GS(TH)</sub>	Gate Threshold Voltage	I <sub>D</sub> =250μA, V <sub>DS</sub> =V <sub>GS</sub>	3	-	5	V
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	I <sub>D</sub> =2A, V <sub>GS</sub> =10V	-	-	3.4	Ω
<b>Dynamic Characteristics</b>						
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> =25V, V <sub>GS</sub> =0, f=1.0MHz	-	1129	-	pF
C <sub>oss</sub>	Output Capacitance		-	65	-	
C <sub>rss</sub>	Reverse Transfer Capacitance		-	5.6	-	
<b>Switching Characteristics</b>						
T <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> =450V, I <sub>D</sub> =4A R <sub>G</sub> =25Ω (Note 3,4)	-	25	60	ns
T <sub>r</sub>	Turn-On Rise Time		-	50	110	
T <sub>d(off)</sub>	Turn-Off Delay Time		-	40	90	
T <sub>f</sub>	Turn-Off Rise Time		-	35	80	
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> =720V, V <sub>GS</sub> =10V, I <sub>D</sub> =4A (Note 3,4)	-	17	22	nC
Q <sub>gs</sub>	Gate-Source Charge		-	4.5	-	
Q <sub>gd</sub>	Gate-Drain Charge		-	7.5	-	
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
I <sub>S</sub>	Max. Diode Forward Current	-	-	-	4	A
I <sub>SM</sub>	Max. Pulsed Forward Current	-	-	-	16	
V <sub>SD</sub>	Diode Forward Voltage	I <sub>D</sub> =4A	-	-	1.4	V
T <sub>rr</sub>	Reverse Recovery Time	I <sub>S</sub> =4A, V <sub>GS</sub> =0V diF/dt=100A/μs	-	450	-	nS
Q <sub>rr</sub>	Reverse Recovery Charge	(Note3)	-	3.5	-	μC

- Notes : 1, L=67mH, I<sub>AS</sub>=4A, V<sub>DD</sub>=50V, R<sub>G</sub>=25Ω, Starting T<sub>J</sub>=25°C  
 2, Repetitive Rating : Pulse width limited by maximum junction temperature  
 3, Pulse Test : Pulse Width ≤ 300μs, Duty Cycle ≤ 2%  
 4, Essentially Independent of Operating Temperature

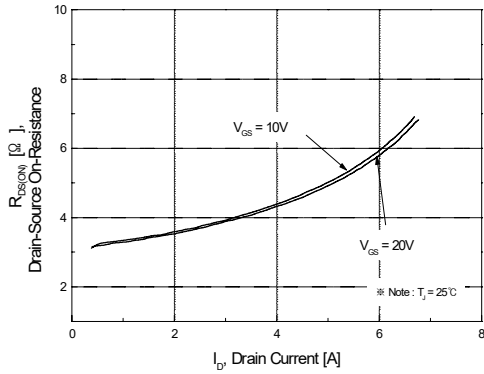
**Typical Characteristics**



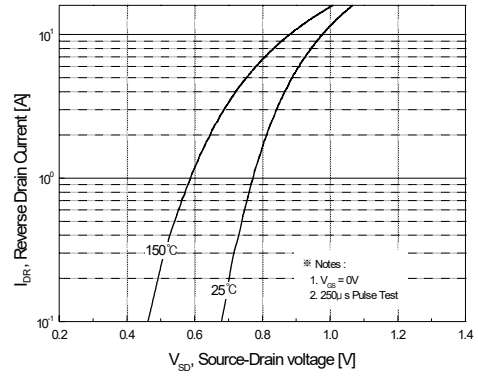
**Figure 1. On-Region Characteristics**



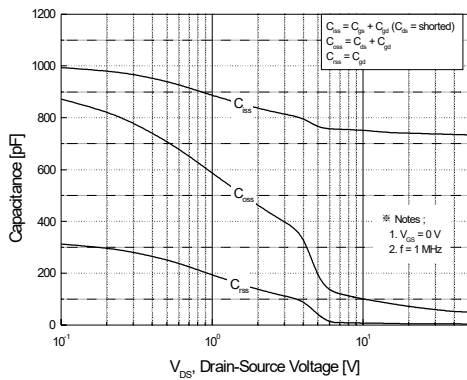
**Figure 2. Transfer Characteristics**



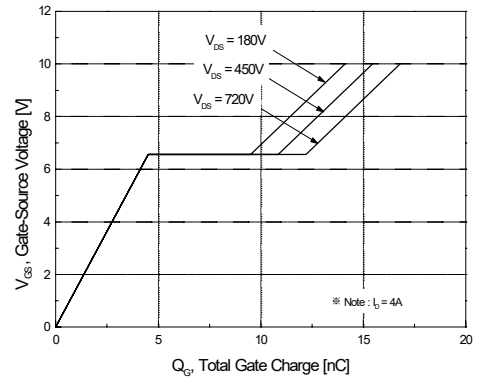
**Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage**



**Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature**



**Figure 5. Capacitance Characteristics**



**Figure 6. Gate Charge Characteristics**

Typical Characteristics (Continued)

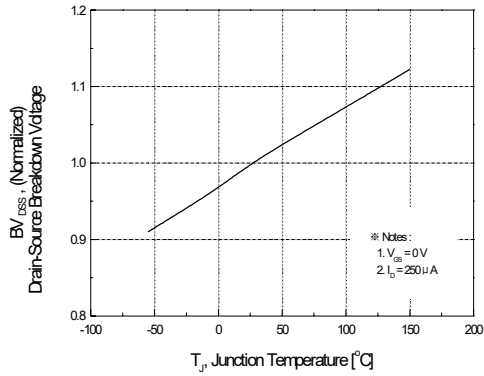


Figure 7. Breakdown Voltage Variation vs Temperature

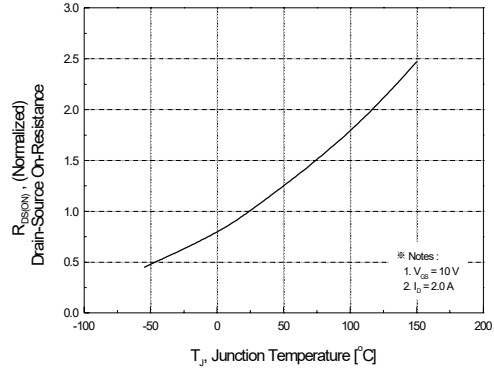


Figure 8. On-Resistance Variation vs Temperature

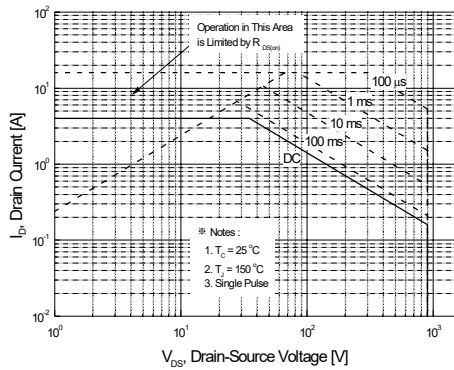


Figure 9-1. Maximum Safe Operating Area

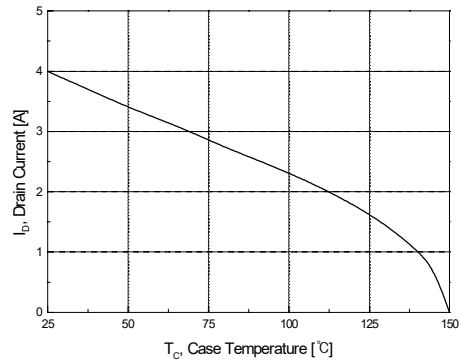


Figure 10. Maximum Drain Current vs Case Temperature

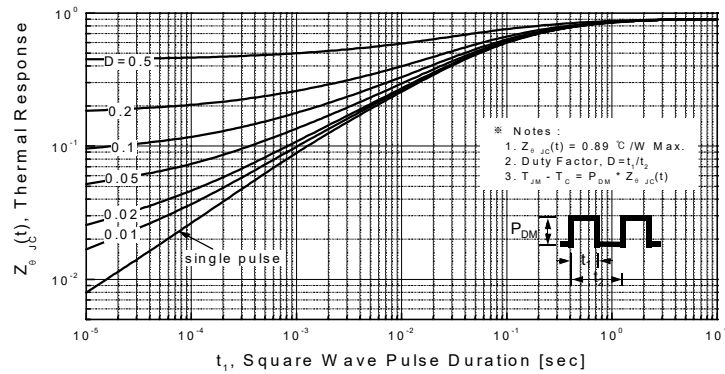
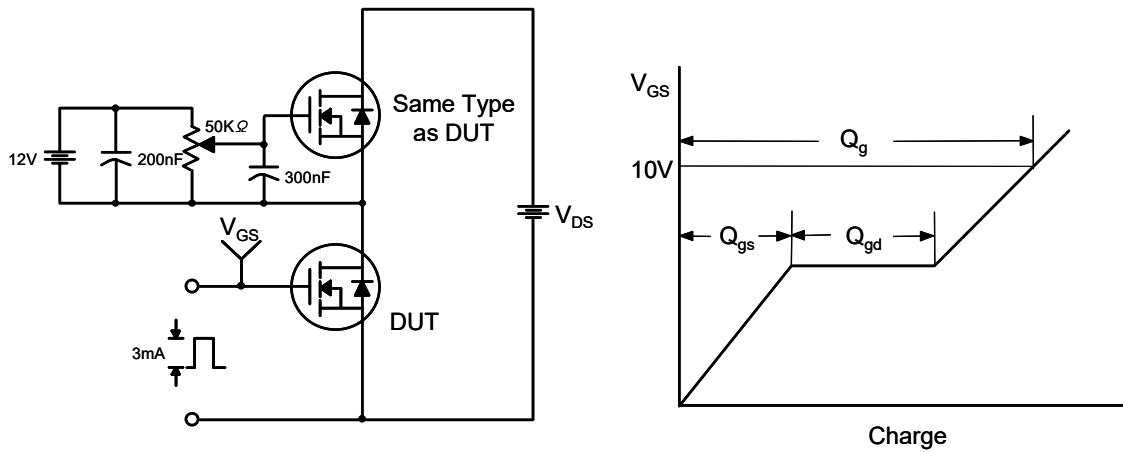
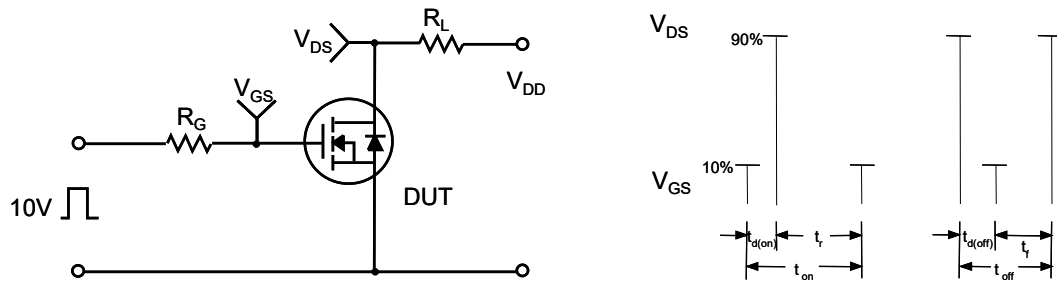


Figure 11-1. Transient Thermal Response Curve

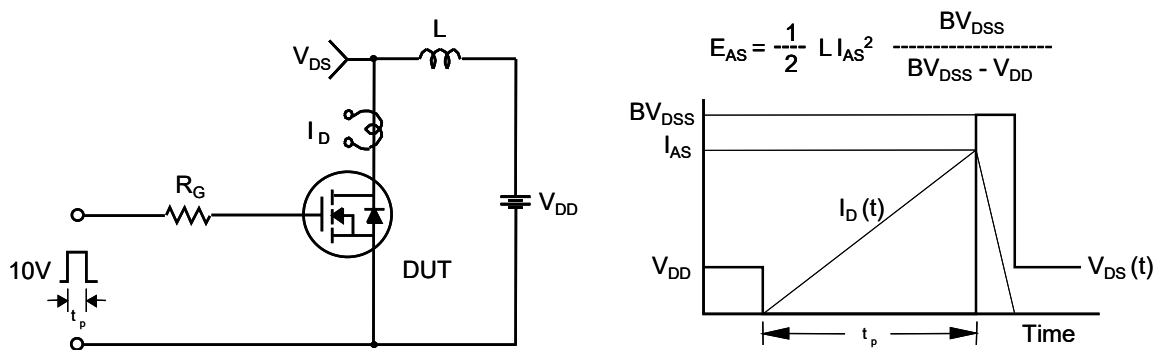
**Gate Charge Test Circuit & Waveform**



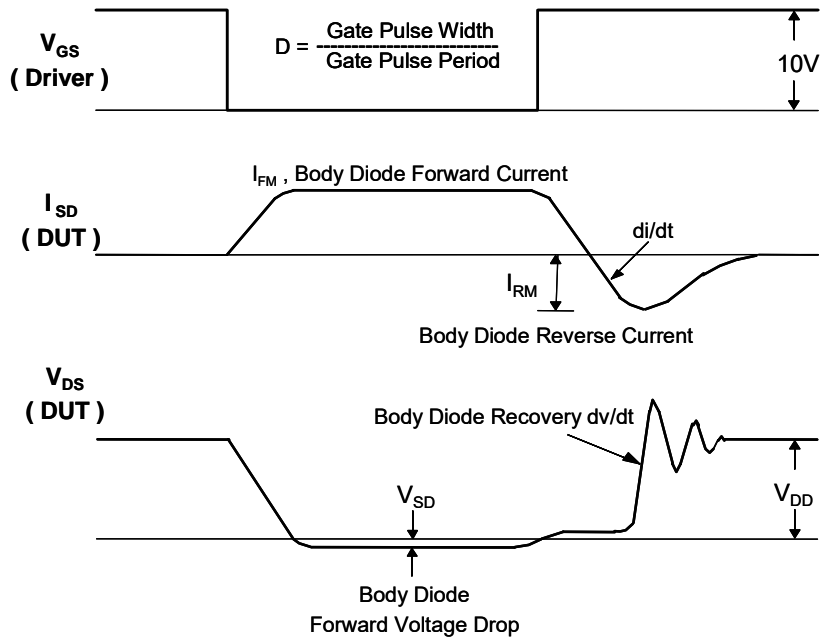
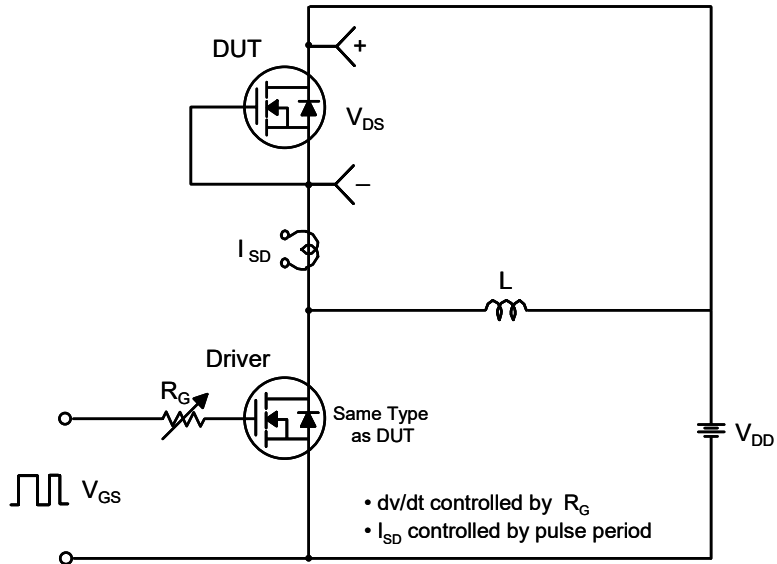
**Resistive Switching Test Circuit & Waveforms**



**Unclamped Inductive Switching Test Circuit & Waveforms**



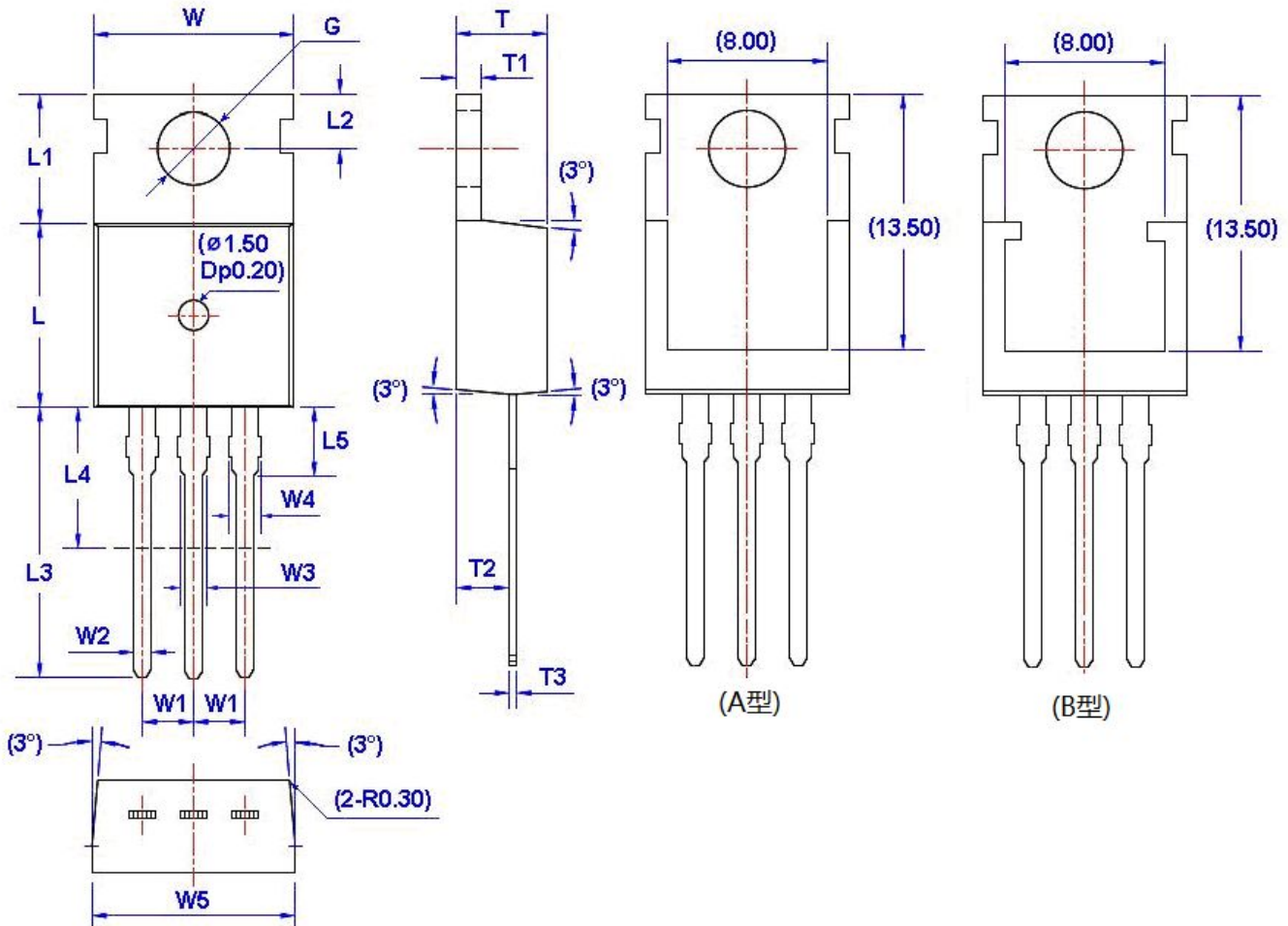
**Peak Diode Recovery dv/dt Test Circuit & Waveforms**



**Package Dimension**

**TO-220**

Unit:mm



Symbol	Size		Symbol	Size		Symbol	Size		Symbol	Size	
	Min	Max		Min	Max		Min	Max		Min	Max
W	9.66	10.28	W5	9.80	10.20	L4**	6.20	6.60	T3	0.45	0.60
W1	2.54 (TYP)		L	9.00	9.40	L5	2.79	3.30	G(Φ)	3.50	3.70
W2	0.70	0.95	L1	6.40	6.80	T	4.30	4.70			
W3	1.17	1.37	L2	2.70	2.90	T1	1.15	1.40			
W4*	1.32	1.72	L3	12.70	14.27	T2	2.20	2.60			